

Test series II

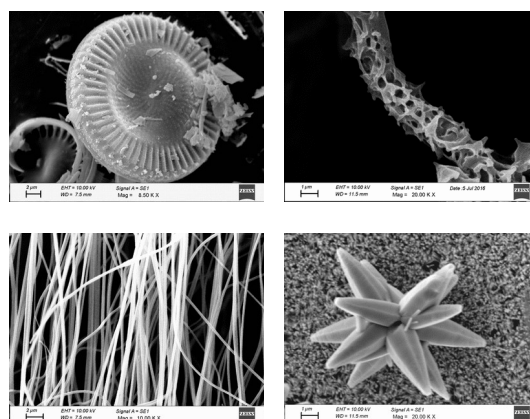
NANOTECH RESEARCH INNOVATION AND INCUBATION CENTRE
PSG INSTITUTE OF ADVANCED STUDIES (PSGIAS)
COIMBATORE

Scanning Electron Microscope (SEM)

Scanning Electron Microscope (SEM) is a non-destructive technique that uses an electron beam to analyze surface details down to nano-scale. PSGIAS has EVO 18 model with low vacuum facility and ALTO 1000 cryo attachment for biological, hydroscopic and sensitive samples. This provides surface topography with a resolution of 3 nm, material composition and distribution of samples ranging from materials Science to biology. It has secondary electron and back scattered electron detection systems along with energy dispersive X ray spectroscopy for elemental analysis and mapping. For hydroscopic or super hydroscopic (gel like) samples low vacuum and cryogenic modes are available. It can operate in several acceleration voltages according to the material requirement and is equipped with various analysis techniques of imaging and composition analysis. The facility is also equipped with sophisticated specimen coating equipments for gold and carbon coating. More details on testing, test charges can be viewed in website <http://www.psgias.ac.in> under test facility & <https://sites.google.com/a/psgias.ac.in/fist/>



SEM NANO IMAGES



Contact: Dr. KK Venkataraman, PSGIAS, +91 9500950311, kkv@psgias.ac.in

Dr. Bindu Salim, PSGIAS, +91 9790039955. bbs@psgias.ac.in

For Technical queries, contact Dr. Amitava Bhattacharya , abh@psgias.ac.in, +91 422 4344000 Extn: 4323